

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination KEOUGH ET AL.	
		Examiner Pablo Whaley	Art Unit 1631	Page 1 of 1

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*	B	US-6,027,890	02-2000	Ness et al.	435/6
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

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	U	Juhasz et al., Proc. Nad. Acad Sci. USA, Vol. 91, pp. 4333-4337
	V	Spengler et al., International Journal of Mass Spectrometry and Ion Process, 1997, Vol. 169/170, p.127-140
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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
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